

Dr.Trupa Sarkar

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Exam Passed	Name of Institution/ University	Specialization
B.Tech	Pondicherry(Central) University	Electronics and Communication Engineering
M.Tech	Tezpur(Central) University	Electronics Design and Technology
Phd (Engineering)	NIT Agartala	Power Aware VLSI Testing

PUBLICATIONS

- [1] **Trupa Sarkar**, M. K. Naskar, A.C. Baishya, P. P. Sahu,” Design of a Two stage RF Operational Amplifier” National Conference on Advances in Video, Cyber Learning and Electronics (ADVCE2012) 01-02 March 2012
- [2] A. Baishya, **Trupa Sarkar**, M. K. Naskar, P. P. Sahu.” A new CMOS voltage controlled ring oscillator for low power radio transceiver applications” Proc. of SPIE Vol. 8760 87601B International Conference on Communication and Electronics System Design(ICCESD – 2013) 28-30 January 2013
- [3] A. Baishya, **Trupa Sarkar**, P. P. Sahu, M. K. Naskar,” Design and Performance Analysis of Low Power RF Operational Amplifier using CMOS and BiCMOS Technology” Proc. of Int. Conf. on Recent Trends in Information, Telecommunication and Computing, ITC March 2014
- [4] **T. Sarkar**, S. Chakraborty and S. N. Pradhan, “Short Survey on Low Power Design and Scan Based VLSI Testing,” “IEEE ICCCA-2015”, Galgotias University, Greater Noida, May 15-16, 2015.
- [5] Shrabanti Chakraborty, **Trupa Sarkar**, Sambhu Nath Pradhan,” Leakage reduction by test pattern reordering” International Conference on Nano-electronics, Circuits & Communication Systems NCCS-2015”, Ranchi, May 9-10, 2015.
- [6] **Trupa Sarkar**, Shrabanti Chakraborty, Bikram Paul & Sambhu Nath Pradhan,” Thermal Aware SOC Testing by Introducing Cooling Period” IETE TECHNICAL REVIEW, 2016 <http://dx.doi.org/10.1080/02564602.2016.1152914>
- [7] Laxmana Maharana, **Trupa Sarkar** and S. N. Pradhan,“Look up Table Based Low Power Analog Circuit Testing”, International Journal of Engineering Transaction C: Aspects Vol. 29, No. 9, (September 2016) 1247-1256
- [8] **Trupa Sarkar**, S.N Pradhan,’Test Power Reduction by Simultaneous Don’t Care Filling and Ordering of Test Patterns Considering Pattern Dependency’ International Journal of Engineering Transaction B: Applications Vol. 31, No. 5, (May 2018) 536-545. (SCOPUS)
- [9] Singh, V. K., **Sarkar T.**, & Pradhan, S. N. (2021). Power-Aware Testing for Maximum Fault Coverage in Analog and Digital Circuits Simultaneously. IETE Technical Review, 1-15. (SCI)
- [10] Munmun Das, **Trupa Sarkar**,” An Optimized Routing Protocol Algorithm for Mobile Ad-hoc Network” Grenze International Journal of Engineering and Technology, 2023, Vol 9, Issue 1, P 185, ISSN 2395-5287.